

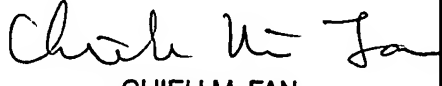
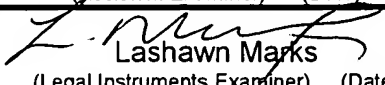


Issue Classification 	Application/Control No.		Applicant(s)/Patent under Reexamination	
	10/050,123		YEN ET AL.	
	Examiner		Art Unit	
	Jason M. Perilla		2638	

ISSUE CLASSIFICATION										
ORIGINAL					CROSS REFERENCE(S)					
CLASS		SUBCLASS			CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)				
375		316			375	324	325			
INTERNATIONAL CLASSIFICATION										
H	0	3	K	9/00						
H	0	4	L	27/06						
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 Jason Perilla 2/16/06 (Assistant Examiner) (Date)		 CHIEH-MEAN CHEN SUPERVISORY PATENT EXAMINER (Primary Examiner) (Date) 2/16/06		Total Claims Allowed: 3	
 Lashawn Marks (Legal Instruments Examiner) (Date)				O.G. Print Claim(s) 1	O.G. Print Fig. 1

<input checked="" type="checkbox"/> Claims renumbered in the same order as presented by applicant					<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47		
Final	Original	Final	Original	Final	Original	Final	Original	Final	Original	Final	Original
	1		31		61		91		121		151
	2		32		62		92		122		152
	3		33		63		93		123		153
	4		34		64		94		124		154
	5		35		65		95		125		155
	6		36		66		96		126		156
	7		37		67		97		127		157
	8		38		68		98		128		158
	9		39		69		99		129		159
	10		40		70		100		130		160
	11		41		71		101		131		161
	12		42		72		102		132		162
	13		43		73		103		133		163
	14		44		74		104		134		164
	15		45		75		105		135		165
	16		46		76		106		136		166
	17		47		77		107		137		167
	18		48		78		108		138		168
	19		49		79		109		139		169
	20		50		80		110		140		170
	21		51		81		111		141		171
	22		52		82		112		142		172
	23		53		83		113		143		173
	24		54		84		114		144		174
	25		55		85		115		145		175
	26		56		86		116		146		176
	27		57		87		117		147		177
	28		58		88		118		148		178
	29		59		89		119		149		179
	30		60		90		120		150		180